



Substituted for form 1449A/PTO <b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b> (Use as many sheets as necessary)	Complete if Known	
	Application Number	09/834,751
	Filing Date	April 13, 2001
	First Named Inventor	Velichko, Sergey
	Group Art Unit	2857
	Examiner Name	Miller, Craig
Sheet 1 of 1		Attorney Docket No: 303.750US1

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EXAMINER

*Manuel L. Barber*

DATE CONSIDERED

*1/19/06*